



CLUSTER DETECTOR TEST REPORT

CLUSTER DETECTOR No. 15
Test carried on 09.12.11 – 10.12.11

Ch.	HEX	U _{op} [V]	U _{op} – 500 V		U _{op}			
			FWHM [keV]	$\frac{FWTM}{FWHM}$	1332 keV			122 keV
					FWHM [keV]	$\frac{FWTM}{FWHM}$	Pos. [Ch.]	FWHM [keV]
A	23	4000	1.99	n.c.	1.90	n.c.	9419	
B	101	4000	2.09	n.c.	1.91	n.c.	6436	
C	11	4000	2.23	n.c.	2.13	n.c.	7803	
D	21	4000	2.08	n.c.	2.03	n.c.	9083	
E	24	4500	1.93	n.c.	1.92	n.c.	9089	
F	26	4000	2.14	n.c.	2.06	n.c.	9707	
G	25	4000	2.10	n.c.	1.98	n.c.	10032	

Operational Temperature: -169.6 °C

Date: 10.12.2011

Tested by:
/I.Kojouharov/

Assembly and test remarks:

Regular test after assembly at RIKEN

Test Equipment:

HV – ORTEC 660

Main Amplifier – ORTEC 671, $\tau = 6 \mu\text{s}$, Gain 100 x 0.72

ADC – 4801A (RIKEN, MCA - PC98B)

Source - ^{60}Co